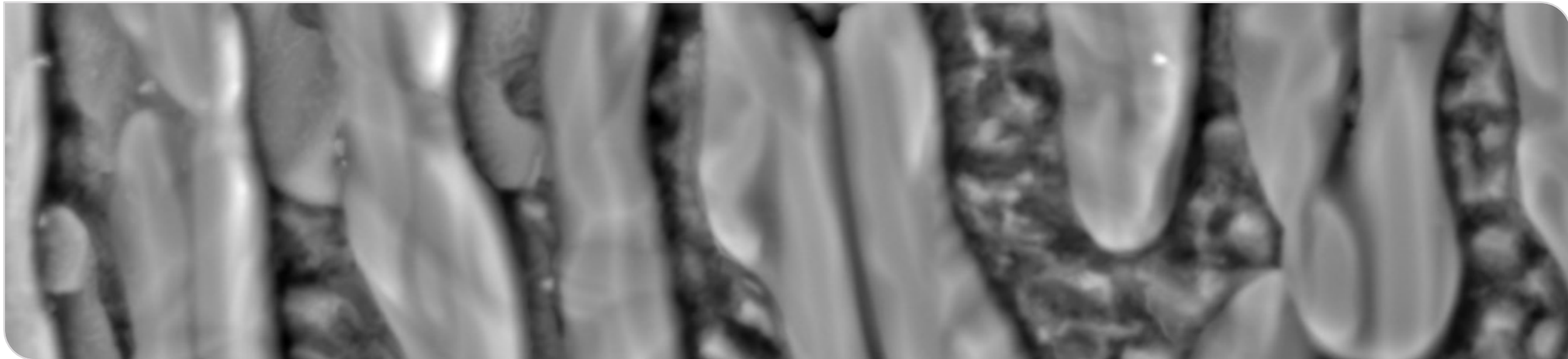


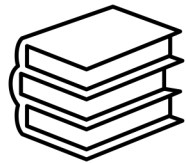
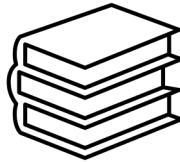
The Scheme for a Metadata Schema

Unlocking the Power of Schemas

Reetu Elza Joseph, Rossella Aversa et al. (Metadata WG of MDMC)



The Reality that We Live in



- Lab books with hand written notes
- No standard languages
- No common vocabularies
- Different measurement techniques do not correlate
- Different instruments for the same measurement technique use different terminologies
- Most ELNs act as stand-alone localised systems with very little use of standards or common practices

We need Schemas and Standards!

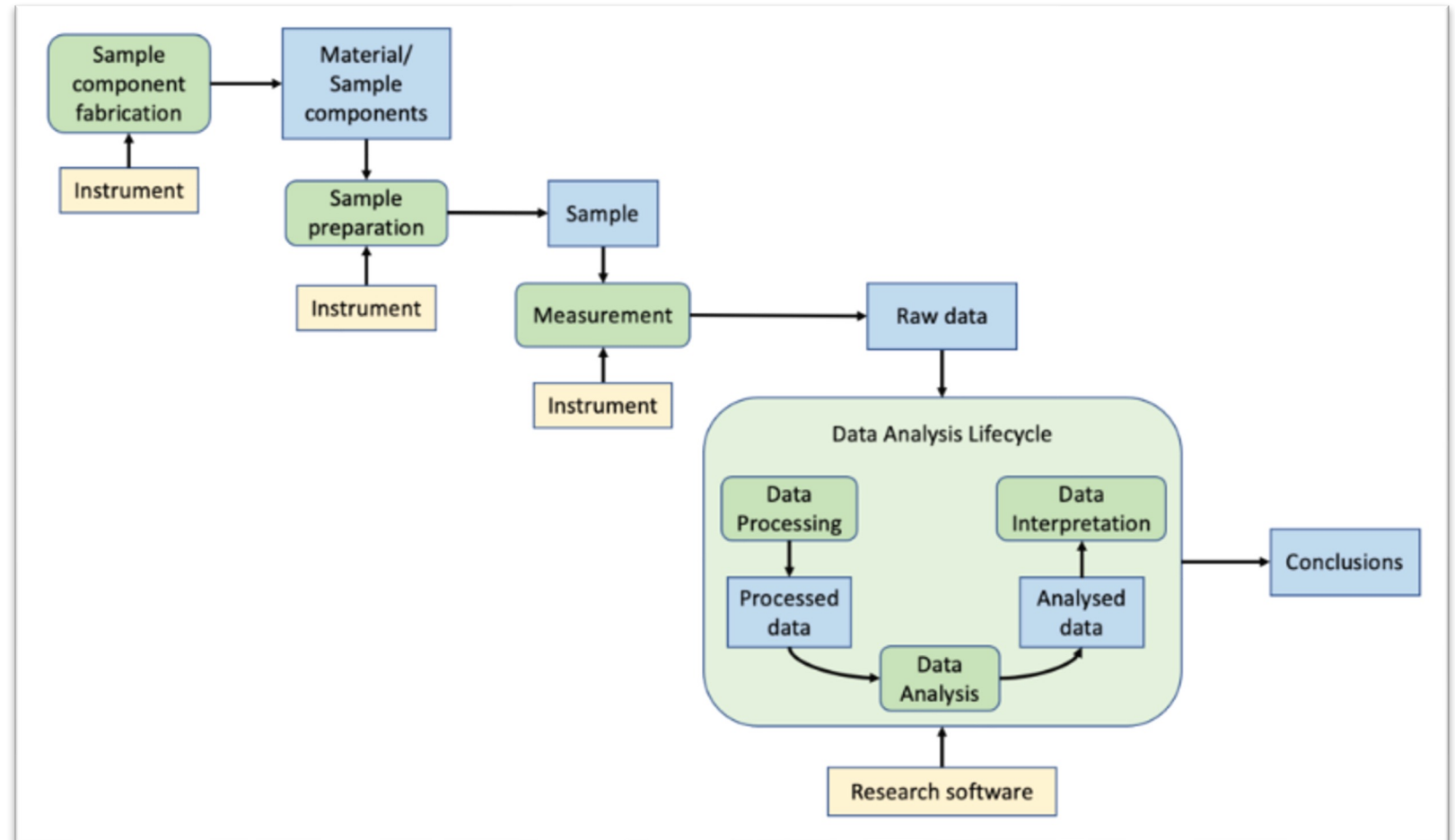
Practical Steps by the Metadata WG

Experimental Workflow of a Study

We defined an **ideal workflow*** using the [MDMC Glossary](#)



available on the [MDMC website](#)



* First published in 2021 in <https://ceur-ws.org/Vol-3036/paper21.pdf>

PRIMA Ontology (PRovenance Information for MAterials Science)

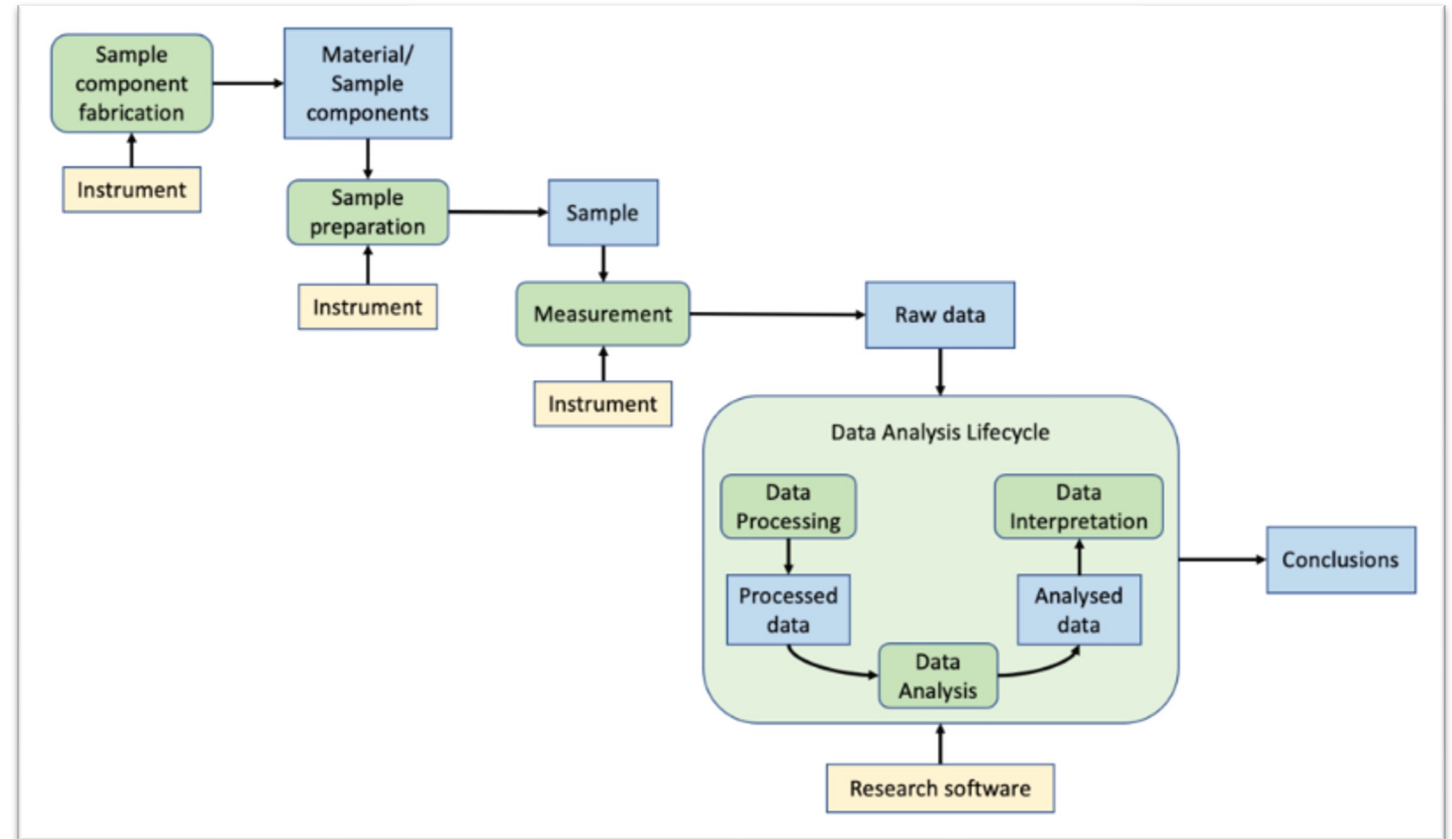
- contains high-level provenance information to describe or annotate the entire experimental workflow.
- Co-developed by the Metadata WG, the [NFFA-Europe Pilot \(NEP\)](#), [EOSC-Pillar](#) and the [Helmholtz Metadata Collaboration \(HMC\)](#)
- More on [MDMC Website](#)

GitHub [page](#) with implementation and competency questions →



Schemas

To be developed for each block of the experimental workflow, inputs and outputs



Schemas: Sample Description

- Under progress
- If interested to contribute, contact us

List of contributors:

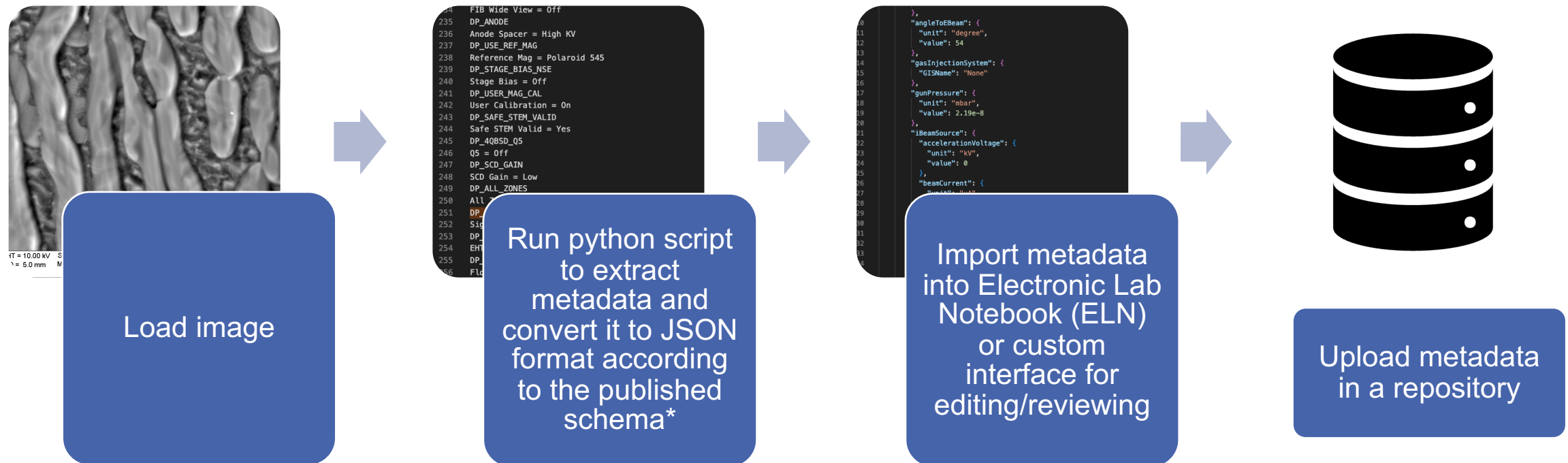
- Rossella Aversa (KIT)
- Richard Thelen (KIT)
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- Alexey Boubnov (KIT)
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Schemas: Measurement Techniques

- Scanning Electron Microscopy (SEM)
- Magnetic Resonance Imaging (MRI)
- Atomic Force Microscopy (AFM)
- Vertical Scanning Interferometer
- Confocal Scanning Microscope
- Transmission Electron Microscope (TEM)
- Nano computed Tomography (nano CT)
- Scanning Tunneling Microscope (STM)



SEM Metadata Extractor and Mapper



* <https://ceur-ws.org/Vol-3036/paper21.pdf>

Contributors: Elias Vitali, Nicolas Blumenröhr (KIT)

Graphical User Interface

Mapping-Service GUI

[Home](#) [Add mapping scheme](#) [Show all mapping schemes](#) [Map a document](#) [REST Documentation](#)

Map a document

Identifier

zeiss_to_json

Enter the ID of the mapping you want to use or select a mapping in the [list of mappings](#).

Document

Choose File  1-as-cast_18_Sch_10k_BSD-Compo.tif

Select the document that should be mapped with an existing mapping.

 Download result

Map document

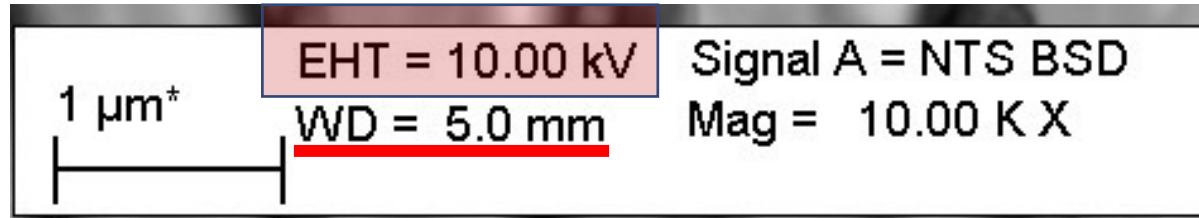


SEM Mapping Tool GUI:
<https://metarepo.nffa.eu/mapping-service/mapDocument.html>

Identifier: **zeiss_to_json**

- uses the python extractor located on GitHub
<https://github.com/kit-data-manager/SEM-Mapping-Tool>

Extracted metadata follows the Schema



```
"instrumentName": "Auriga 60",  
"stage": {  
  "eBeamWorkingDistance": {  
    "unit": "mm",  
    "value": 4.967  
  },  
  "stageAlignmentDone": true,  
  "tiltAngle": {  
    "unit": "degree",  
    "value": 0  
  }  
}
```

```
"eBeamSource": {  
  "accelerationVoltage": {  
    "unit": "kV",  
    "value": 10  
  },  
  "beamCurrent": {  
    "unit": "μA",  
    "value": 80  
  }  
},  
"imaging": {  
  "apertureSetting": {  
    "size": {  
      "unit": "μm",  
      "value": 120  
    }  
  }  
}
```

```
"sample": {  
  "sampleHolder": "Carousel 8x6.5mm",  
  "sampleSize": {  
    "unit": "mm",  
    "value": 10  
  }  
}
```

Import Metadata Document for Viewing/Editing

- Electronic Lab Notebooks
 - Schema can be imported as a template
 - Enable relevant fields for correlative characterisation
 - Metadata WG - ELN Developers
 - Catriona Eschke (Herbie)
 - Nicole Jung (Chemotion)
 - Michael Selzer (Kadi4Mat)
- Metadata should be uploaded in a repository like the MetaStore, which registers a schema, and then metadata can be validated against the schema fulfilling FAIR principles

Custom Interface to Add, Review and Correct Metadata

SEM Metadata Editor



Validation

Click to upload JSON document

Acceleration Voltage **i**

Value **i**

10

Unit **i**

kV

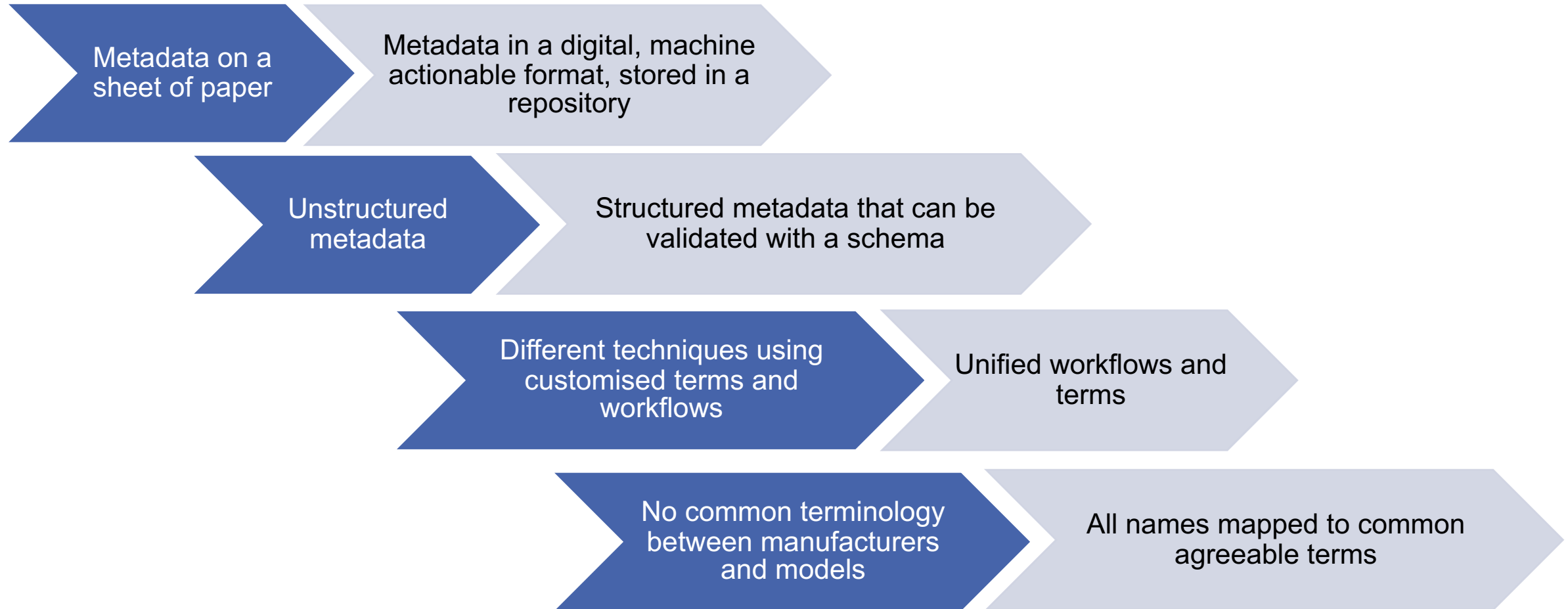
Download

- Based on the published schema
- With drop down menus
- Information on each field
- Integrated schema validation

Available at: <https://kit-data-manager.github.io/Metadata-Schemas-for-Materials-Science/>



Past vs Future with Schemas



Conclusions and Future Work

- Following schemas facilitates FAIR principles and eases correlative characterization
- Working with ELN developers for enabling schema or relevant fields import
- More Schemas in development



Call to action:
drop an email to rossella.aversa@kit.edu